

Title (en)

METHOD AND DEVICE FOR TESTING CIRCUIT BOARDS

Title (de)

VERFAHREN UND VORRICHTUNG ZUM TESTEN VON LEITERPLATTEN

Title (fr)

PROCEDE ET DISPOSITIF POUR TESTER DES CARTES DE CIRCUITS

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Application

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Abstract (en)

[origin: WO0140809A1] The invention relates to a method and device for testing circuit boards (5), by means of a parallel tester, comprising a contact arrangement, with several test contacts for simultaneous contacting of several circuit board test points (4), on a circuit board under test. Said method comprises the following steps: placing the circuit board to be tested on the contact arrangement, such that at least the circuit board test points of a first region (I), on the circuit board to be tested, are in contact with test contacts of a first region of the contact arrangement; carrying out a first test process in said first region; moving the circuit board, in relation to the test arrangement, by a predetermined amount, such that at least circuit board test points of a second region of the circuit board to be tested come into contact with test contacts of a second region (II), of the contact arrangement; carrying out a second test measurement process in said second region. The disclosed method permits circuit boards with a warp or misalignment to be tested with a parallel tester.

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